

Notice of References Cited			Application/Control No.	Applicant(s)/Patent Under Reexamination 10/767,364 YEH ET AL.	
			Examiner Mei Q. Huang	Art Unit 1713	Page 1 of 1

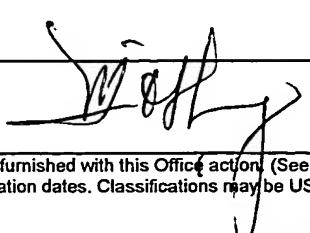
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,309,707	10-2001	Mayer et al.	427/386
*	B	US-5,032,641	07-1991	Nanishi et al.	524/544
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	M	US-			

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*	N	JP 06-345823	12-1994	Japan	Shunichi et al.	
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NON-PATENT DOCUMENTS

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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